

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Beaman et al.

Serial No.: 09/382,834

Filed: August 25, 1999

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,
TEST PROBE AND METHODS OF USE THEREOFCommissioner for Patents
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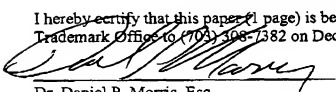
Group Art Unit: 2829

Examiner: V. P. Nguyen

Docket No.: YO993-028BX

Sir:

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this paper (1 page) is being facsimile transmitted to the U.S. Patent and
Trademark Office to (703) 308-7382 on December 3, 2003.
Dr. Daniel P. Morris, Esq.
Reg. No. 32,053Letter

Applicants note that the claims of the present application, in particular claims 29-52, appear to be substantially similar to the Claims of US patent 5,806,181. Please charge deposit account 09-0468 any fee to enter this paper and any previously submitted paper for the above identified application.


Respectfully submitted,By: _____
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